In-depth study of Inverse-Low Gain Avalanche Detectors (ILGAD) for 4-dimensional tracking and radiation tolerance assessment of thin LGADs



Esteban CurrásInstituto de Física de Cantabria (CSIC-UC)







Instituto de Física de Cantabria



The Team

E. Currás, J. Duarte, M. Fernández, A. García, G. Gómez, J. González, R. Jaramillo, D. Moya, I. Vila. **Instituto de Física de Cantabria(CSIC-UC)**

M. Moll, M. Centis, M. Wiehe.

CERN

M. Carulla, D. Flores, S. Hidalgo, A. Merlos, G. Pellegrini, S. Otero Ugobono, D. Quirion. **IMB-CNM (CSIC)**

Developed inside the RD50 collaboration & AIDA -2020 WP7 on Advanced Hybrid Detectors.













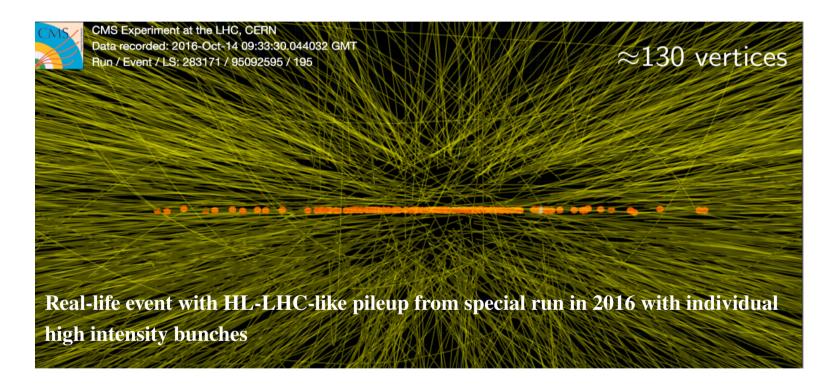






Motivation

High-luminosity LHC upgrade: ATLAS and CMS experiment are planning to include dedicated detector systems to measure the arrival time of Minimum Ionizing Particles (**MIPs**).



Pile-up mitigation (up to 200) \rightarrow time resolution needed of ~30 ps per MIP. Increase of the detector radiation tolerance \rightarrow up to ~ 3E15 n_{eq}/cm².

Radiation tolerance assessment of thin LGADs

Devices description

LGADs produced by CNM (run 11748).

Devices under study coming from two different wafers with different active thicknesses (d):

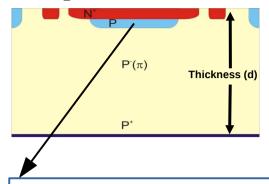
- $d = 50 \mu m$
- $d = 35 \mu m$

Also PIN diodes for reference.

Study plan

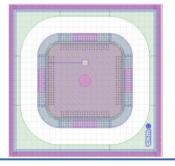
- 1. Electrical characterization. 🗸
- 2. Irradiated at CERN PS with 24 GeV protons at 5 different fluences. 🗸
 - $6E13 n_{eq}/cm^2$
 - $1E14 \text{ n}_{eq}/\text{cm}^2$
 - $3E14 \text{ n}_{eq}/\text{cm}^2$
 - $1E15 \text{ n}_{eq}/\text{cm}^2$
 - $3E15 n_{eq}/cm^2$
- 3. Annealing right after irradiation of 10 minutes at 60 °C. 🗸
- 4. Electrical characterization after irradiation. ✓
- 5. Laser measurement: Gain studies. ... ongoing.
- 6. Laser measurement: timing studies. **X** ... to be done.

A pad-like LGAD



Highly doped gain layer Signal amplification Better SNR !!

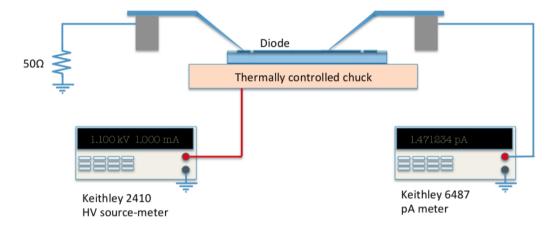




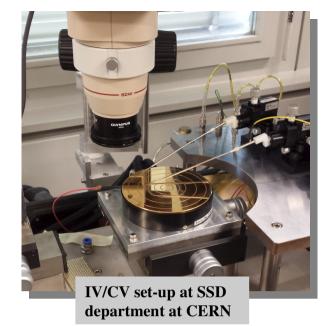
Total area of 2.6x2.6 mm² Active area of 1.3x1.3 mm² Intermediate gain (1.8E13)

Electrical characterization

 $IV \rightarrow Measure$ of the leakage current as a function of the bias voltage.



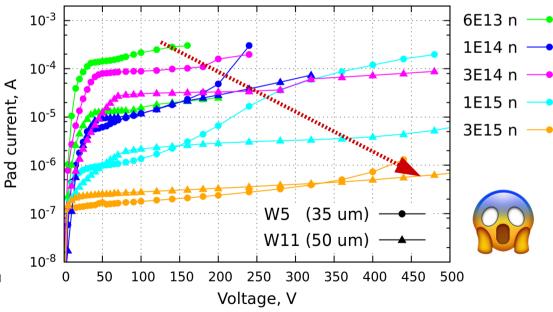
IV (35 um vs 50 um) T: 20C unirradiated



IV (35 um vs 50 um), T: -20C, irradiated

10⁻³
10⁻⁴
10⁻⁵
10⁻⁶
Very high leakage current !!

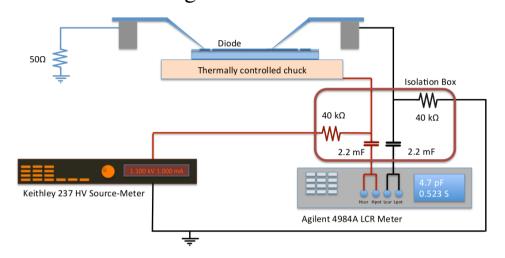
0 20 40 60 80 100 120 140 160 180 200 220
Voltage, V



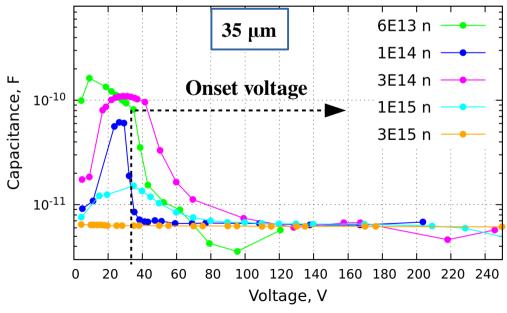
The higher the fluence the lower the leakage current !!

Electrical characterization

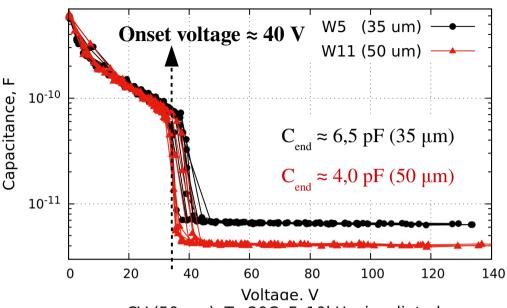
 $CV \rightarrow Measure$ of the capacitance as a function of the bias voltage.



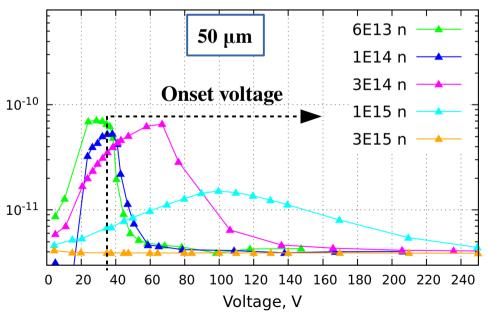
CV (35 um), T: -20C, F: 10kHz, irradiated



CV (35 um vs 50 um), T: 20C, F: 1 kHz, unirradiated



CV (50 um), T: -20C, F: 10kHz, irradiated

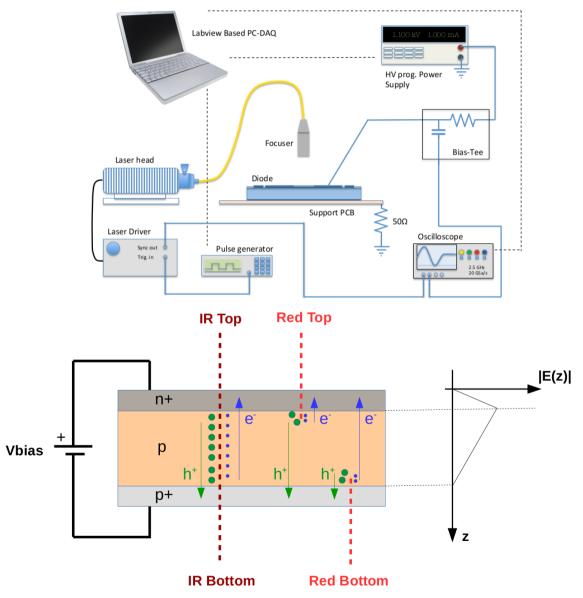


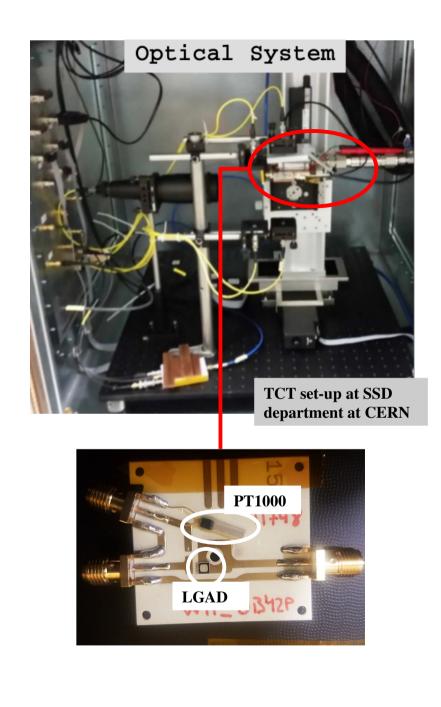
Esteban Curras - 15th VCI - February 2019

Capacitance,

Laser measurements: Gain studies

Transient Current Technique (TCT) working principle



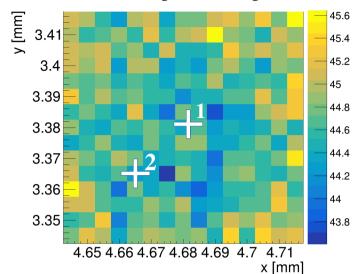


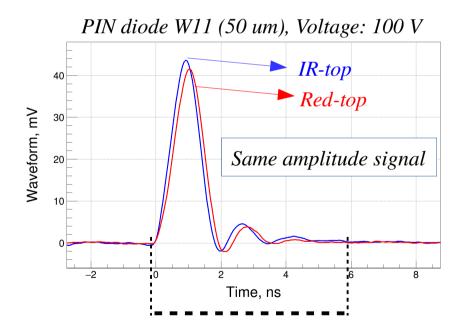
Laser measurements: Gain studies

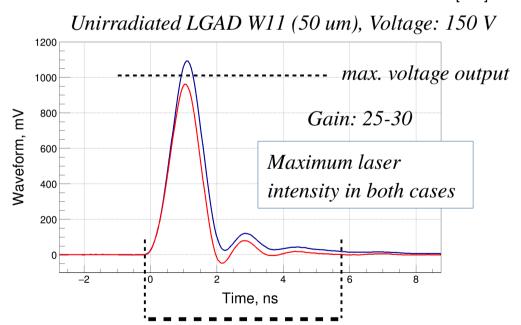
2D amplitude map, mV

Measurements set-up and waveforms

- IR laser and red laser
- Top illumination
- Same laser intensity in both cases
- Temperature: -20 C
- Amplifier: CIVIDEC C2, 2 GHz, 40 dB
- Osciloscope: Agilent DSO 9254, 2.5 GHz, 20 GSa/s
 - Averaging of 256 to improve SNR



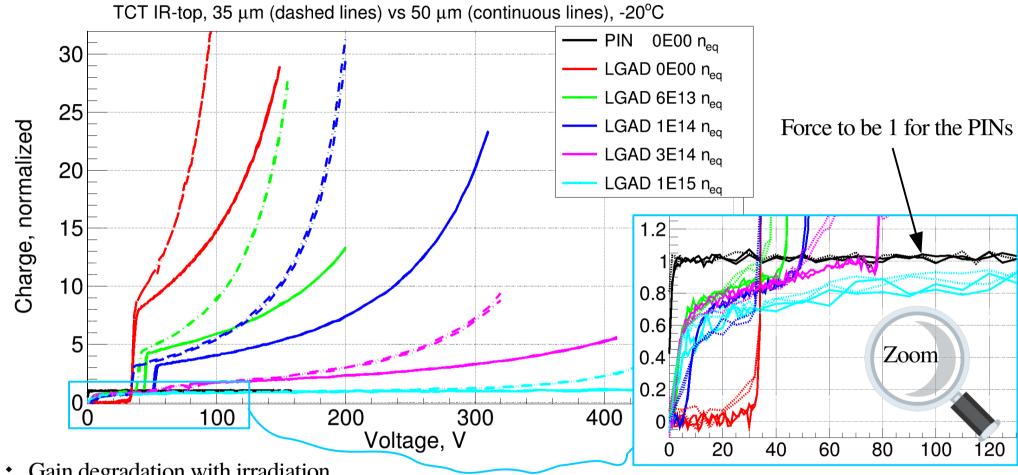




Charge collection measured by the pulse integral within the first 6 ns.

Laser measurements: Gain studies

IR laser measurements 35 um (dashed lines) vs 50 um (continuous lines)

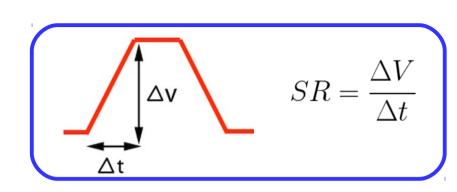


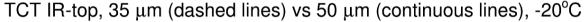
- Gain degradation with irradiation
- Increase of the amplification onset with irradiation: hint of double-junction mechanism (consistent with the capacitance measurements)
- Acceptor removal effect can not be extracted from the onset voltage
- Better behavior of thin sensors

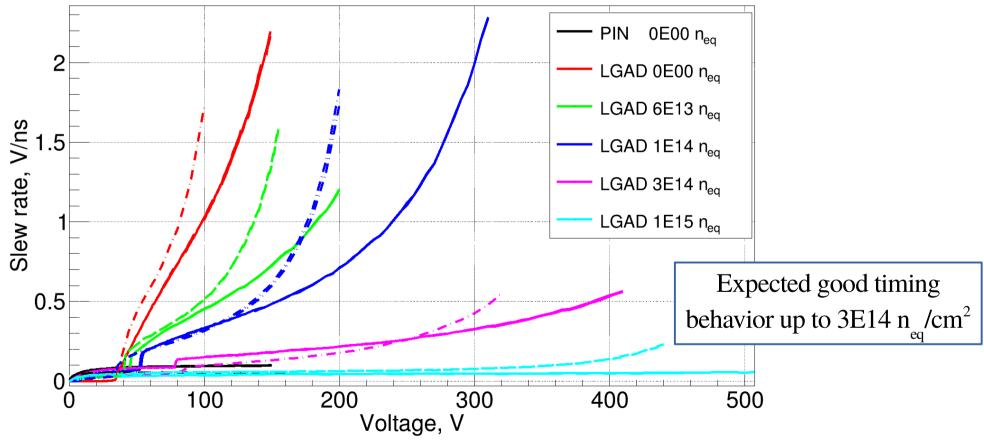
Laser measurements: Slew rate (SR)

IR laser measurements 35 um vs 50 um

$$\delta_{time} \propto \frac{\delta_{noise}}{\left|\frac{dV}{dt}\right|} \propto \frac{\Delta t}{\Delta V} * \delta_{noise} = \frac{\delta_{noise}}{SR}$$







Radiation tolerance assessment of thin LGADs:

Conclusions and outlook

- Very high leakage current observed: problem under investigation.
- We still observe amplification up to a fluence of $3E14 \text{ n}_{eq}/\text{cm}^2$.
- Better behavior observed for the thinner devices.

Bias voltage needed for a SR value of 0.5:

Fluence (neq)	0.00E+00	6.00E+13	1.00E+14	3.00E+14	1.00E+15
35 um	54 V	98 V	132 V	312 V	X
50 um	64 V	110 V	152 V	390 V	X

- → Need to complete laser measurements, including noise studies.
- → Perform timing measurements:
 - → Infrared laser.
 - → Sr-90 source.

In-depth study of Inverse-Low Gain Avalanche Detectors (ILGAD) for 4-dimensional tracking

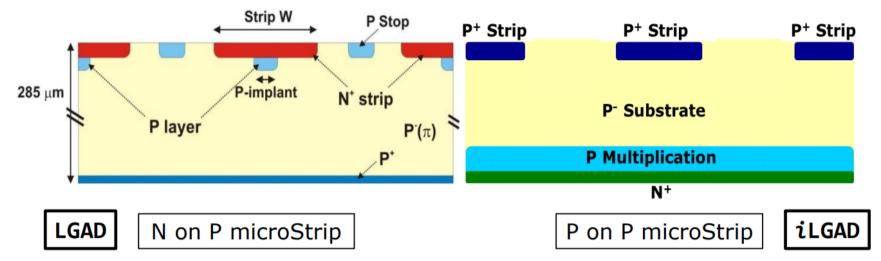
I-LGAD basics: a 4th dimensional tracking sensor

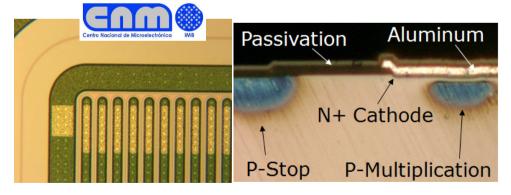
Multiplication layer divided into strip Collects negative carriers (e)

Simple single side process

Multiplication layer extended over the electrode Collects positive carriers (h)

Complex double side process





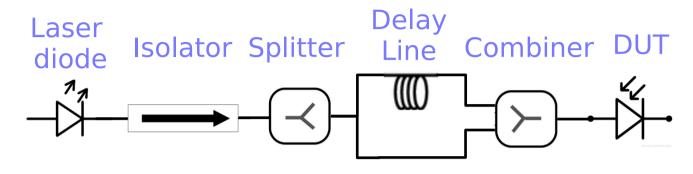
*The fill factor issue: gain spatial uniformity

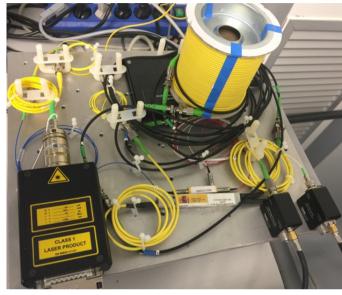
- LGAD: multiplication layer inter-space presents reduced/suppressed gain.
- I-LGAD: non-segmented multiplication layer should present uniform gain.

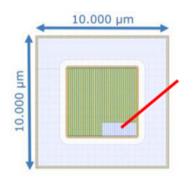
 $https://indico.cern.ch/event/666427/contributions/2881813/attachments/1603622/2544525/20180219_I-LGAD_IvanVila.pdf$

^{*} Fill factor studies were presented at Trento workshop 2017→ Link to the talk

Set-up for timing characterization and DUTs







I-LGAD strip
45 strips
Thickness 285 um
Pitch 160 um



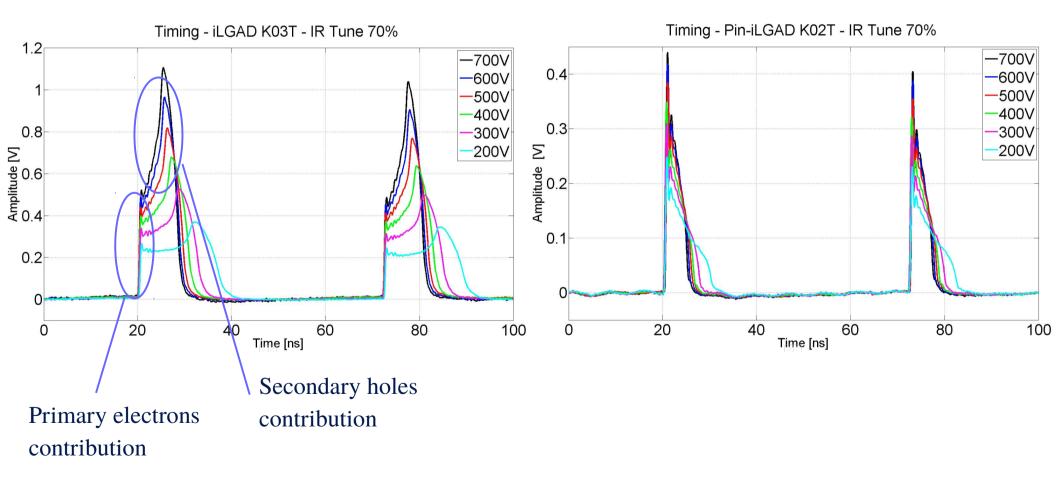
PIN strip
90 strips
Thickness 285 um
Pitch 80 um

- Time standard: constant time interval between two picosecond IR laser pulses (1060 nm)
- Fixed time interval between laser pulses generated by optical splitting and delayed recombination of a single laser pulse.
- External time reference is not needed.

* Strips \rightarrow small electrode capacitance \rightarrow good for timing studies

Set-up for timing characterization and DUT (2)

- Signal amplified (60db, miteq 1660) & digitized (25GSa/s)
- Acquired averaged waveform from I-LGAD and PIN sensors with a time interval of 52.23 ns between pulses



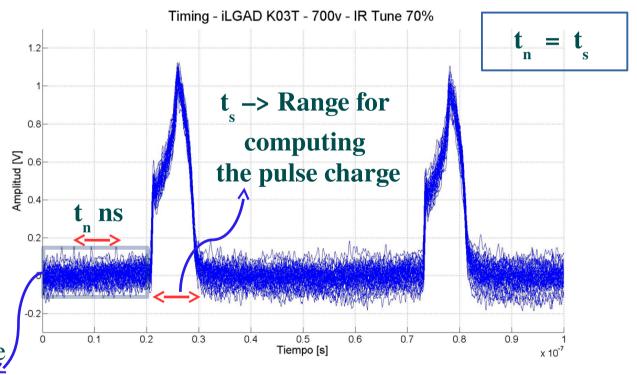
Parameter extraction of the waveform.

- Single-shot (non-averaged) superposition of signals.
- For each shot measured: Rise time, Signal amplitude and noise.
- **Signal estimation** as the charge under the transient waveform.
- **Noise estimation** as the RMS of charge (from the first nanoseconds of the waveform).

 $\sigma \equiv RMS$ (Charge baseline)

$$SNR \equiv rac{Signal\ Charge}{\sigma}$$

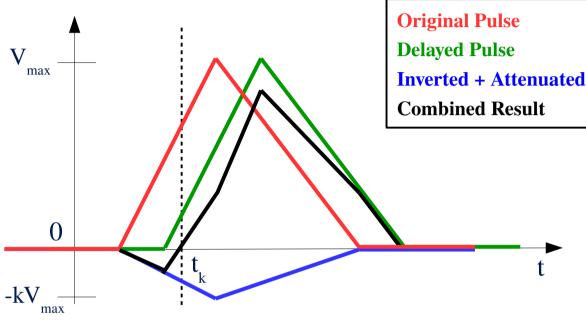
Waveform section from where the baseline noise is estimated



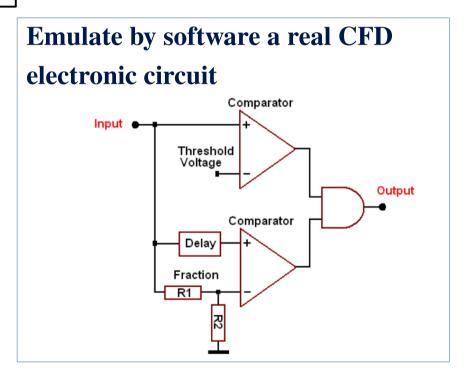
Timing computation:

Constant Fraction Discrimination method (CFD)

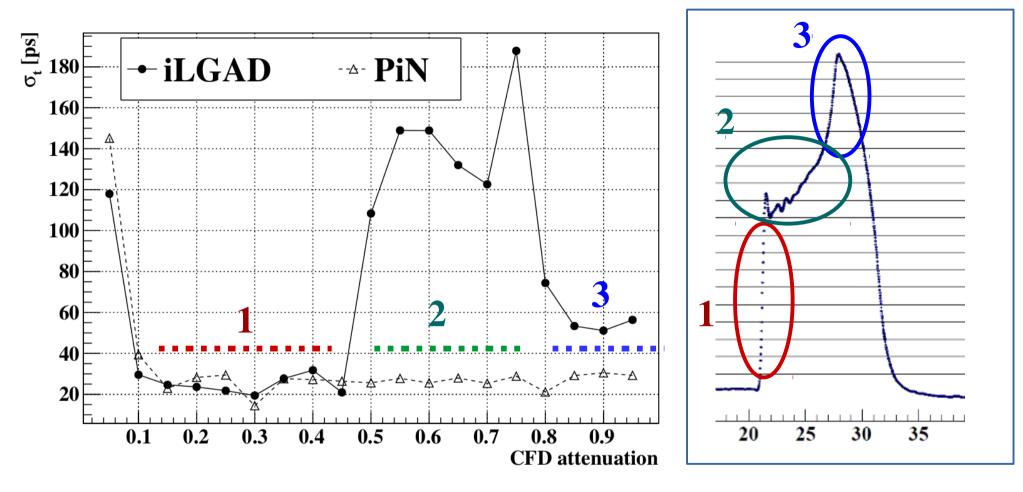
CFD principles of operation



- > Split the input signal in two parts
- Delay on part
- > Attenuate (-kV_{max}) and invert the other
- Add the two signals together
- ➤ The zero crossing point of the bipolar signal (t_k) will always be constant

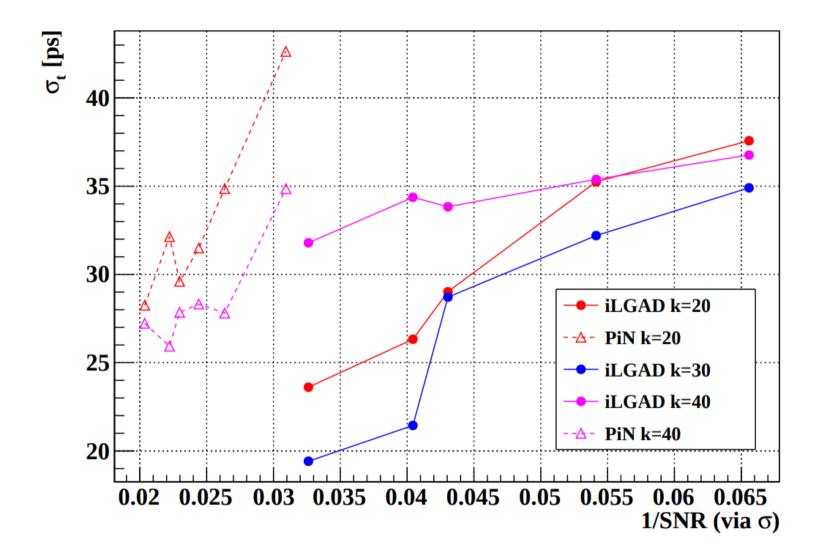


Constant Fraction Discrimination method (CFD):



- > Optimum value of the k parameter for the I-LGAD in zone 1.
- For the PIN k parameter is optimum in almost the full range.

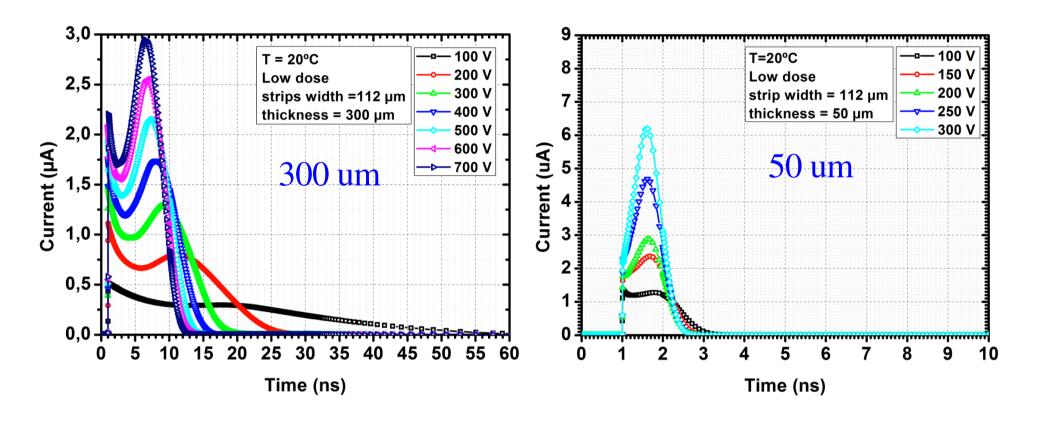
Constant Fraction Discrimination method (CFD):



Better time resolution for the I-LGAD even with lower SNR.

Constant Fraction Discrimination method (CFD):

Simulation 300 um vs 50 um.



- First part of the signal very fast and good for timing but not as good in SNR terms.
- Second part still good with better SNR but worse rise time.
- If we go to 50 um we can have both benefits: Good SNR and low rise time.

In-depth study of Inverse-Low Gain Avalanche Detectors (ILGAD) for 4-dimensional tracking:

Conclusions and outlook

- We compared the timing performance of one I-LGAD strip sensor with a similar PIN strip sensor.
- Time resolution was estimated using a more realistic CFD method.
- Better time resolution with the I-LGAD sensor for a lower SNR.
- → Simulations show a promising time performance of 50 um I-LGADs strip devices.

Thank you for your attention!!